

512 K (32 K x 16) Static RAM

Features

- Pin-and function-compatible with CY7C1020CV33
- High speed

 □ t_{AA} = 10 ns
- Low active power
 □ I_{CC} = 60 mA @ 10 ns
- Low CMOS standby power
 □ I_{SB2} = 3 mA
- 2.0 V Data retention
- Automatic power-down when deselected
- CMOS for optimum speed/power
- Independent control of upper and lower bits
- Available in Pb-free 44-pin 400-Mil wide Molded SOJ and 44-pin TSOP II packages

Functional Description

The CY7C1020DV33 is a high-performance CMOS static RAM organized as 32,768 words by 16 bits. This device has an automatic power-down feature that significantly reduces power consumption when deselected.

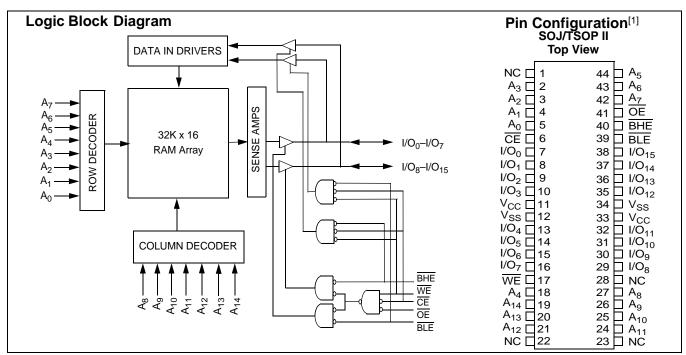
Writing to the device is <u>acc</u>omplished by taking chip enable (\overline{CE}) and write enable (\overline{WE}) inputs LOW. If byte low enable (\overline{BLE}) is LOW, then data from I/O pins $(I/O_0$ through $I/O_7)$, is written into the location specified <u>on the address pins</u> $(A_0$ through $A_{14})$. If byte high enable (\overline{BHE}) is LOW, then data from I/O pins $(I/O_8$ through $I/O_{15})$ is written into the location specified on the address pins $(A_0$ through $A_{14})$.

Reading <u>from</u> the device is accomplished by taking chip enable (CE) <u>and</u> output enable (OE) LOW <u>while</u> forcing the write enable (WE) HIGH. If byte low enable (BLE) is LOW, then data from the memory location specified by the <u>add</u>ress pins will appear on I/O $_0$ to I/O $_7$. If byte high enable (BHE) is LOW, then data from memory will appear on I/O $_8$ to I/O $_15$. See the truth table at the back of this data sheet for a complete description of read and write modes.

The input/output pins (I/O $_0$ through I/O $_{15}$) are placed in a high-impedance state when the <u>device</u> is desel<u>ected</u> (CE_HIGH), the <u>outputs are disabled</u> (OE HIGH), the BHE and BLE are disable<u>d</u> (BHE, BLE HIGH), or during a write operation (CE LOW, and WE LOW).

The CY7C1020DV33 is available in Pb-free 44-pin 400-Mil wide Molded SOJ and 44-pin TSOP II packages.

For a complete list of related documentation, click here.



Notes

1. NC pins are not connected on the die.



Selection Guide

	-10 (Industrial)	Unit
Maximum access time	10	ns
Maximum operating current	60	mA
Maximum CMOS standby current	3	mA

Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.) Storage temperature-65 °C to +150 °C Ambient temperature with power applied –55 °C to +125 °C Supply voltage on V_{CC} to Relative $GND^{[2]}$...-0.5 V to +4.6 V DC voltage applied to outputs in High-Z State $^{[2]}$-0.5 V to V_{CC} + 0.5 V

DC input voltage ^[2]	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Current into outputs (LOW)	20 mA
Static discharge voltage(per MIL-STD-883, Method 3015)	> 2001 V
Latch-up current	> 200 mA

Operating Range

Range	Ambient Temperature	V _{CC}	Speed
Industrial	–40 °C to +85 °C	$3.3 \text{ V} \pm 0.3 \text{ V}$	10 ns

Electrical Characteristics Over the Operating Range

Doromotor	Decerinties	Test Conditions		–10 (In	dustrial)	l lmi4
Parameter	Description	rest Conditions		Min.	Max.	Unit
V _{OH}	Output HIGH voltage	V_{CC} = Min., I_{OH} = -4.0 mA		2.4		V
V _{OL}	Output LOW voltage	$V_{CC} = Min., I_{OL} = 8.0 \text{ mA}$			0.4	V
V _{IH}	Input HIGH voltage			2.0	V _{CC} + 0.3	V
V _{IL}	Input LOW voltage ^[2]			-0.3	0.8	V
I _{IX}	Input Load current	$GND \le V_1 \le V_{CC}$	$GND \le V_I \le V_{CC}$		+1	μΑ
I _{OZ}	Output leakage current	$GND \le V_1 \le V_{CC}$, Output Disable	ed	-1	+1	μА
I _{CC}	V _{CC} operating	V _{CC} = Max.,	100 MHz		60	mA
	supply current	$I_{OUT} = 0 \text{ mA},$ $f = f_{MAX} = 1/t_{RC}$	83 MHz		55	mA
			66 MHz		45	mA
			40 MHz		30	mA
I _{SB1}	Automatic CE Power-down Current—TTL Inputs	Max. V_{CC} , $\overline{CE} \ge V_{IH}$ $V_{IN} \ge V_{IH}$ or $V_{IN} \le V_{IL}$, $f = f_{MAX}$			10	mA
I _{SB2}	Automatic CE Power-down Current—CMOS Inputs	$\begin{array}{l} \text{Max. V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V}, \\ \text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V}, \text{ or V}_{\text{IN}} \leq 0.3 \text{ V} \end{array}$	/, f = 0		3	mA

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Notes 2. V_{IL} (min.) = -2.0 V and V_{IH} (max) = V_{CC} + 1 V for pulse durations of less than 5 ns.



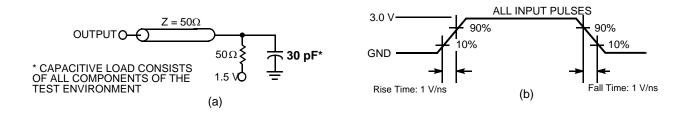
Capacitance^[3]

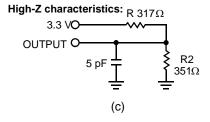
Parameter	Description Test Conditions		Max.	Unit
C _{IN}	Input capacitance	$T_A = 25^{\circ}C$, $f = 1$ MHz, $V_{CC} = 3.3$ V	8	pF
C _{OUT}	Output capacitance		8	pF

Thermal Resistance^[3]

Parameter	Description	Test Conditions	SOJ	TSOP II	Unit
Θ_{JA}		Still air, soldered on a 3 × 4.5 inch, four-layer printed circuit board	59.52	53.91	°C/W
Θ _{JC}	Thermal resistance (Junction to Case)		36.75	21.24	°C/W

AC Test Loads and Waveforms[4]





Notes

- 3. Tested initially and after any design or process changes that may affect these parameters.
- 4. AC characteristics (except High-Z) are tested using the load conditions shown in Figure (a). High-Z characteristics are tested for all speeds using the test load shown in Figure (c).



Switching Characteristics Over the Operating Range [5]

	5	-10 (Inc	dustrial)	
Parameter	Description	Min.	Max.	Unit
Read Cycle		1	-	1
t _{power} ^[6]	V _{CC} (typical) to the first access	100		μS
t _{RC}	Read cycle time	10		ns
t _{AA}	Address to data valid		10	ns
t _{OHA}	Data Hold from Address Change	3		ns
t _{ACE}	CE LOW to data valid		10	ns
t _{DOE}	OE LOW to data valid		5	ns
t _{LZOE}	OE LOW to Low-Z ^[7]	0		ns
t _{HZOE}	OE HIGH to High-Z ^[7, 8]		5	ns
t _{LZCE}	CE LOW to Low-Z ^[7]	3		ns
t _{HZCE}	CE HIGH to High-Z ^[7, 8]		5	ns
t _{PU} ^[9]	CE LOW to Power-up	0		ns
t _{PD} ^[9]	CE HIGH to Power-down		10	ns
t _{DBE}	Byte enable to data valid		5	ns
t _{LZBE}	Byte enable to low-Z	0		ns
t _{HZBE}	Byte disable to high-Z		5	ns
Write Cycle ^[10, 11]		1	-1	1
t _{WC}	Write cycle time	10		ns
t _{SCE}	CE LOW to write end	8		ns
t _{AW}	Address set-up to write end	8		ns
t _{HA}	Address hold from write end	0		ns
t _{SA}	Address set-up to write start	0		ns
t _{PWE}	WE pulse width	7		ns
t _{SD}	Data set-up to write end	5		ns
t _{HD}	Data hold from write end	0		ns
t _{LZWE} WE HIGH to Low-Z ^[7]		3		ns
t _{HZWE}	WE LOW to High-Z ^[7, 8]		5	ns
t _{BW}	Byte enable to end of write	7		ns

Notes

- 5. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V.

 6. t_{POWER} gives the minimum amount of time that the power supply should be at typical V_{CC} values until the first memory access can be performed

 7. t_{HZOE}, t_{HZBE}, t_{HZCE}, and t_{HZWE} are specified with a load capacitance of 5 pF as in (c) of AC Test Loads. Transition is measured when the outputs enter a high impedance state.

 8. At any given temperature and voltage condition, t_{HZCE} is less than t_{LZCE}, t_{HZOE} is less than t_{LZCE}, and t_{HZWE} for any given device.

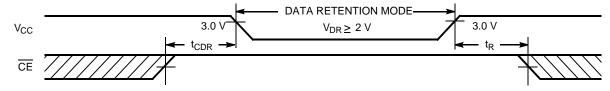
- This parameter is guaranteed by design and is not tested.
 The internal Write time of the memory is defined by the overlap of CE LOW, WE LOW and BHE/BLE LOW. CE, WE and BHE/BLE must be LOW to initiate a Write and the transition of these signals can terminate the Write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the Write.
 The minimum write cycle time for Write Cycle 3 (WE controlled, OE LOW) is the sum of thzwe and tsp.



Data Retention Characteristics (Over the Operating Range)

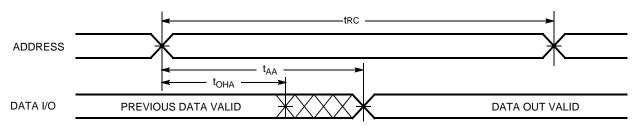
Parameter	Description	Conditions	Min.	Max.	Unit
V_{DR}	V _{CC}		2.0		V
I _{CCDR}	Data retention current	$V_{CC} = V_{DR} = 2.0 \text{ V}, \overline{CE} \ge V_{CC} - 0.3 \text{ V},$ Industrial $V_{IN} \ge V_{CC} - 0.3 \text{ V}$ or $V_{IN} \le 0.3 \text{ V}$		3	mA
t _{CDR} [3]	Chip deselect to data retention time		0		ns
t _R ^[12]	Operation recovery time		t _{RC}		ns

Data Retention Waveform

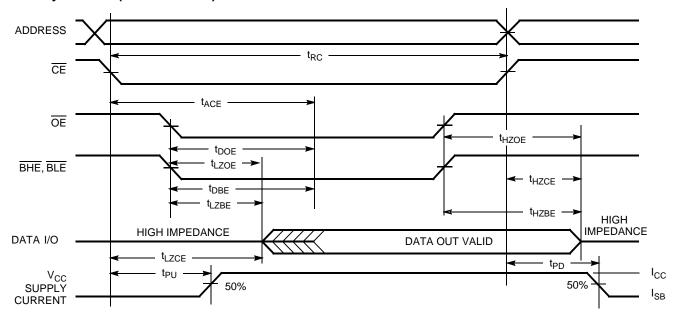


Switching Waveforms

Read Cycle No. 1 (Address Transition Controlled)[13, 14]



Read Cycle No. 2 (OE Controlled)[14, 15]



- 12. Full device operation requires lin<u>ear V_{CC} ramp</u> from V_{DR} to V_{CC(min.)} ≥ 50 μs or stable at V_{CC(min.)} ≥ 50 μs.

 13. Device is continuously selected. OE, CE, BHE and/or BLE = V_{IL}.

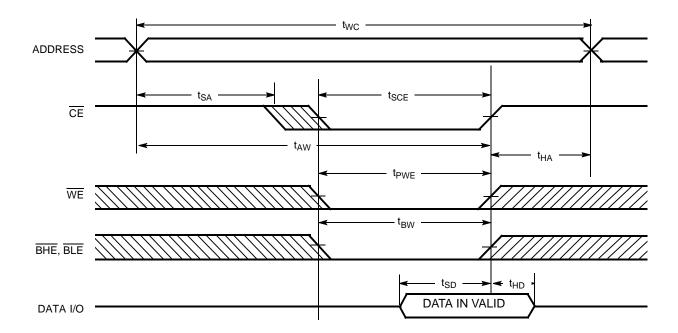
 14. WE is HIGH for Read cycle.

 15. Address valid prior to or coincident with CE transition LOW.

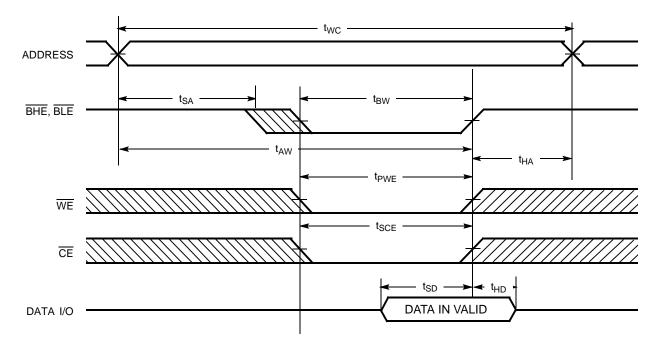


Switching Waveforms (continued)

Write Cycle No. 1 (CE Controlled)[16, 17]



Write Cycle No. 2 (BLE or BHE Controlled)



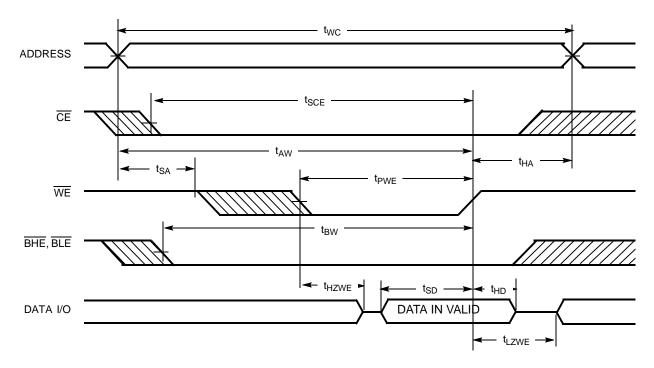
^{16.} Data I/O is high impedance if \overline{OE} or \overline{BHE} and/or $\overline{BLE} = V_{IH}$.

17. If \overline{CE} goes HIGH simultaneously with \overline{WE} going HIGH, the output remains in a high-impedance state.



Switching Waveforms (continued)

Write Cycle No. 3 (WE Controlled, OE LOW)



Truth Table

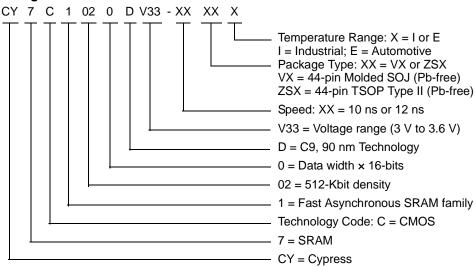
CE	OE	WE	BLE	BHE	I/O ₀ -I/O ₇	I/O ₈ –I/O ₁₅	Mode	Power
Н	Х	Х	X	X	High-Z	High-Z	Power-down	Standby (I _{SB})
L	L	Н	L	L	Data Out	Data Out	Read—All bits	Active (I _{CC})
			L	Н	Data Out	High-Z	Read—Lower bits only	Active (I _{CC})
			Н	L	High-Z	Data Out	Read—Upper bits only	Active (I _{CC})
L	Х	L	L	L	Data In	Data In	Write—All bits	Active (I _{CC})
			L	Н	Data In	High-Z	Write—Lower bits only	Active (I _{CC})
			Н	L	High-Z	Data In	Write—Upper bits only	Active (I _{CC})
L	Н	Н	Х	Х	High-Z	High-Z	Selected, Outputs Disabled	Active (I _{CC})
L	Х	Х	Н	Н	High-Z	High-Z	Selected, Outputs Disabled	Active (I _{CC})



Ordering Information

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
10	CY7C1020DV33-10ZSXI	51-85087	44-pin TSOP Type II (Pb-free)	Industrial

Ordering Code Definitions

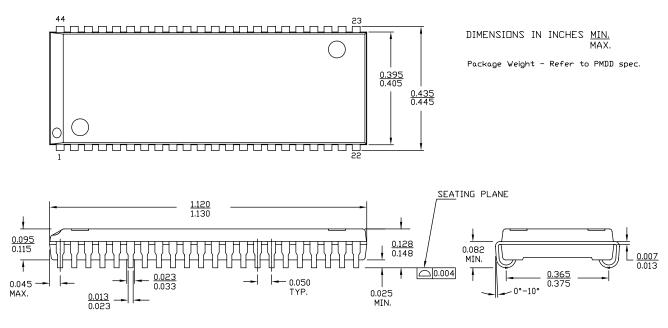


Shaded areas contain advance information. Please contact your local Cypress sales representative for availability of these parts.



Package Diagrams

Figure 1. 44-pin (400-Mil) Molded SOJ (51-85082)

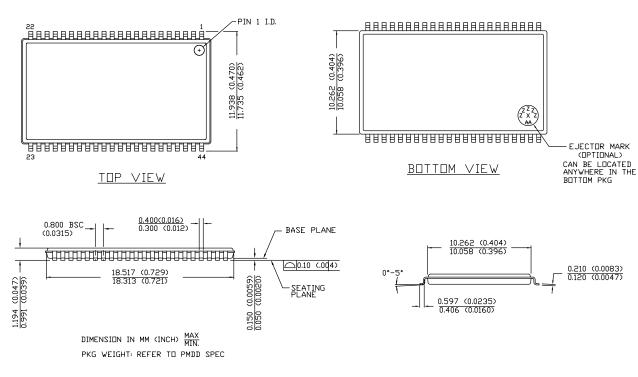


51-85082 *E



Package Diagrams (continued)

Figure 2. 44-Pin Thin Small Outline Package Type II (51-85087)



51-85087 *E



Acronyms

Acronym	Description
BHE	byte high enable
BLE	byte low enable
CE	chip enable
CMOS	complementary metal oxide semiconductor
I/O	input/output
ŌĒ	output enable
SRAM	static random access memory
TSOP	thin small outline package
WE	write enable

Document Conventions

Units of Measure

Symbol	Unit of Measure
°C	degrees Celsius
μΑ	microamperes
mA	milliamperes
MHz	megahertz
ns	nanoseconds
pF	picofarads
V	volts
Ω	ohms
W	watts



Document History Page

REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change
**	201560	See ECN	SWI	Advance Information data sheet for C9 IPP
*A	233695	See ECN	RKF	DC parameters modified as per EROS (Spec # 01-02165) Pb-free Offering in Ordering Information
*B	262950	See ECN	RKF	Changed I/O ₁ – I/O ₁₆ to I/O ₀ – I/O ₁₅ Added Data Retention Characteristics table Added T _{power} spec in Switching Characteristics table Added 44-SOJ package diagram Shaded Ordering Information
*C	307596	See ECN	RKF	Reduced Speed bins to -8 and -10 ns
*D	560995	See ECN	VKN	Converted from Preliminary to Final Removed Commercial operating range Removed 8 ns speed bin Added Automotive information Added I _{CC} values for the frequencies 83MHz, 66MHz and 40MHz Updated Thermal Resistance table Updated Ordering Information table Changed Overshoot spec from V _{CC} +2 V to V _{CC} +1 V in footnote #4
*E	2898399	03/24/2010	AJU	Updated Package Diagrams
*F	3109992	12/14/2010	AJU	Added Ordering Code Definitions.
*G	3424450	10/28/2011	TAVA	Updated footnotes Updated Selection Guide, Operating Range, Electrical Characteristics Over the Operating Range, Switching Characteristics Over the Operating Range [5], Data Retention Characteristics (Over the Operating Range), Switching Waveforms, and Ordering Information. Updated Package Diagrams Added Acronyms, and Document Conventions
*H	3861347	01/08/2013	TAVA	Updated Ordering Information (Updated part numbers). Updated Package Diagrams: spec 51-85082 – Changed revision from *D to *E. spec 51-85087 – Changed revision from *D to *E.
*	4574311	11/19/2014	TAVA	Added related documentation hyperlink in page 1. Added note 11 in Switching Characteristics Over the Operating Range [5]. Added note reference in the Switching Characteristics table.



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